



# HGTG20N60A4D alternative

IGBT Transistors 600V 70A 290W TO247



## HGTG20N60A4D alternative Datasheet

### 600V Trench and Fieldstop IGBT

PRODUCT SUMMARY		
$V_{CE}$ (V)	600	
$I_C$ (A)	8.0 (TC=25°C)	40 (TC=100°C)
$V_{CE(sat)}$ (V)	1.8	
$I_{CM}$ (A)	120	

#### FEATURES

- Very Low  $V_{CEsat}$
- Low turn-off losses
- High speed switching
- Maximum junction temperature 175°C
- Ultra low gate charge ( $Q_g$ )
- Avalanche energy rated (UIS)



RoHS  
COMPLIANT  
HALOGEN  
FREE

#### APPLICATIONS

- Telecommunications
  - Server and telecom power supplies
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Consumer and computing
  - ATX power supplies
- Industrial
  - Welding
  - Battery chargers
- Renewable energy
  - Solar (PV inverters)
- Switch mode power supplies (SMPS)

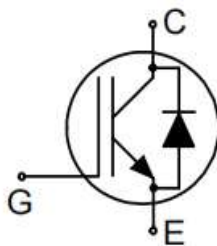
#### Package pin definition

- Pin1 G - Gate
- Pin2 C & backside - Collector
- Pin3 E - Emitter

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Top View



ABSOLUTE MAXIMUM RATINGS ( $T_C = 25^\circ\text{C}$ , unless otherwise noted)					
PARAMETER		SYMBOL	LIMIT	UNIT	
Collector-Emitter Voltage		$V_{CE}$	600	V	
Gate-Emitter Voltage		$V_{GE}$	$\pm 30$		
Continuous Collector Current ( $T_J = 150^\circ\text{C}$ )	$V_{GE}$ at 15 V	$I_C$	$T_C = 25^\circ\text{C}$	80	A
			$T_C = 100^\circ\text{C}$	40	
Pulsed Collector Current <sup>a</sup>		$I_{CM}$	120		
Diode Forward Current <sup>b</sup>		$I_F$	40	A	
Maximum Power Dissipation		$P_D$	$T_C = 25^\circ\text{C}$	248	W
			$T_C = 100^\circ\text{C}$	126	W
Operating Junction and Storage Temperature Range		$T_J, T_{stg}$	-55 to +175	$^\circ\text{C}$	
Short Circuit Withstand Time $T_C=150^\circ\text{C}$	$V_{GE} = 15\text{V}, V_{CE} \leq 400\text{V}$		3	$\mu\text{s}$	
Short Circuit Withstand Time $T_C=100^\circ\text{C}$	$V_{GE} = 15\text{V}, V_{CE} \leq 330\text{V}$				
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s		260	$^\circ\text{C}$	

#### Notes

- Repetitive rating; pulse width limited by maximum junction temperature.
- Current limited by maximum junction temperature.
- 1.6 mm from case.

THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	$R_{thJA}$	-	40	°C/W
Maximum Junction-to-Case	$R_{thJC}$	-	0.5	

SPECIFICATIONS ( $T_J = 25\text{ °C}$ , unless otherwise noted)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
<b>Static</b>							
Collector-Emitter Breakdown Voltage	$BV_{CE}$	$V_{GE} = 0\text{ V}, I_C = 250\text{ }\mu\text{A}$ $V_{GE} = 0\text{ V}, I_C = 1\text{ mA}$		600 600	- -	- -	V
Gate-Source Threshold Voltage (N)	$V_{GE(th)}$	$V_{CE} = V_{GE}, I_D = 250\text{ }\mu\text{A}$		4	5	6	V
Zero Gate Voltage Collector Current	$I_{CES}$	$V_{CE} = 600\text{ V}, V_{GE} = 0\text{ V}, T_J = 25\text{ °C}$		-	1	20	$\mu\text{A}$
		$V_{CE} = 600\text{ V}, V_{GE} = 0\text{ V}, T_J = 150\text{ °C}$		-	1000	-	$\mu\text{A}$
Gate-Emitter Leakage Current	$I_{GES}$	$V_{CE} = 0\text{ V}, V_{GS} = \pm 20\text{ V}$		-	-	100	nA
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$	$V_{GE} = 15\text{ V}$	$I_C = 40\text{ A}$	-	1.8	2.1	V
Forward Transconductance	$g_{fs}$	$V_{CE} = 20\text{ V}, I_C = 40\text{ A}$		-	17	-	S
<b>Dynamic</b>							
Input Capacitance	$C_{ies}$	$V_{GE} = 0\text{ V}, V_{CE} = 25\text{ V},$ $f = 500\text{ KHz}$		-	4600	-	pF
Output Capacitance	$C_{oes}$			-	186	-	
Reverse Transfer Capacitance	$C_{res}$			-	148	-	
Turn-on Energy	$E_{on}$	$V_{CE} = 400\text{ V}, V_{GE} = 0/15\text{V},$ $I_C = 40\text{ A}, R_g = 10\Omega$		-	23	-	nJ
Turn-off Energy	$E_{off}$			-	0.8	-	
Total Gate Charge	$Q_g$	$V_{GE} = 20\text{ V}$	$I_C = 40\text{ A}, V_{CE} = 400\text{ V}$	-	36	-	nC
Gate-Emitter Charge	$Q_{ge}$			-	76	-	
Gate to Collector Charge	$Q_{gc}$			-	138	-	
Turn-On Delay Time	$t_{d(on)}$	$V_{CE} = 400\text{ V}, V_{GE} = 0/15\text{V},$ $I_C = 40\text{ A}, R_g = 10\Omega$		-	56	-	ns
Rise Time	$t_r$			-	47	-	
Turn-Off Delay Time	$t_{d(off)}$			-	176	-	
Fall Time	$t_f$			-	36	-	
Internal emitter inductance measured 5 mm	$L_E$			-	13	-	nH
<b>Diode Characteristics</b>							
Diode Forward Current	$I_F$	IGBT symbol showing the integral reverse junction diode		-	-	40	A
Pulsed Diode Forward Current	$I_{FM}$			-	-	120	
Diode Forward Voltage	$V_F$	$I_F = 40\text{ A}$		-	1.64	2.0	V
Reverse Recovery Time	$t_{rr}$	$T_J = 25\text{ °C}, I_F = 40\text{ A},$ $dI_F/dt = 200\text{ A}/\mu\text{s}, V_R = 400\text{ V}$		-	55	-	ns
Reverse Recovery Charge	$Q_{rr}$			-	0.31	-	$\mu\text{C}$
Reverse Recovery Current	$I_{RRM}$			-	13	-	A

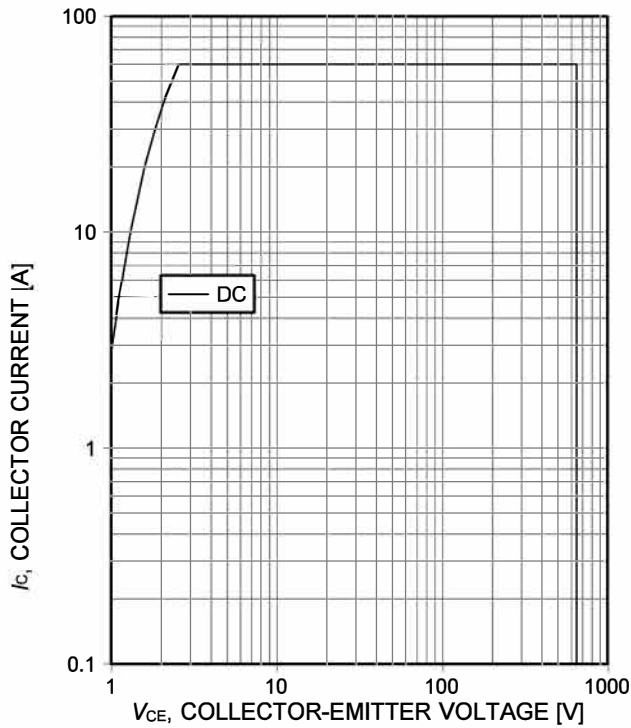


Figure 1. **Forward bias safe operating area**  
 ( $D=0$ ,  $T_C=25^\circ\text{C}$ ,  $T_{vj}\leq 175^\circ\text{C}$ ;  $V_{GE}=15\text{V}$ .  
 Recommended use at  $V_{GE}\geq 7.5\text{V}$ )

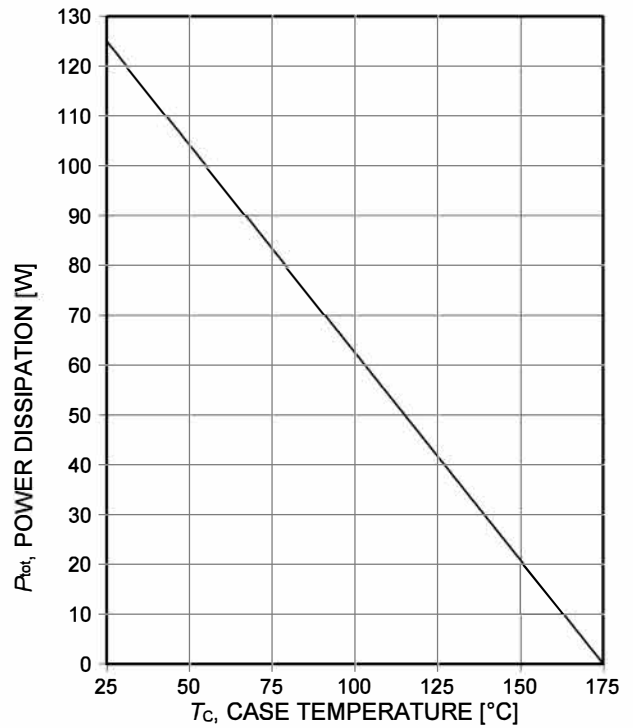


Figure 2. **Power dissipation as a function of case temperature**  
 ( $T_{vj}\leq 175^\circ\text{C}$ )

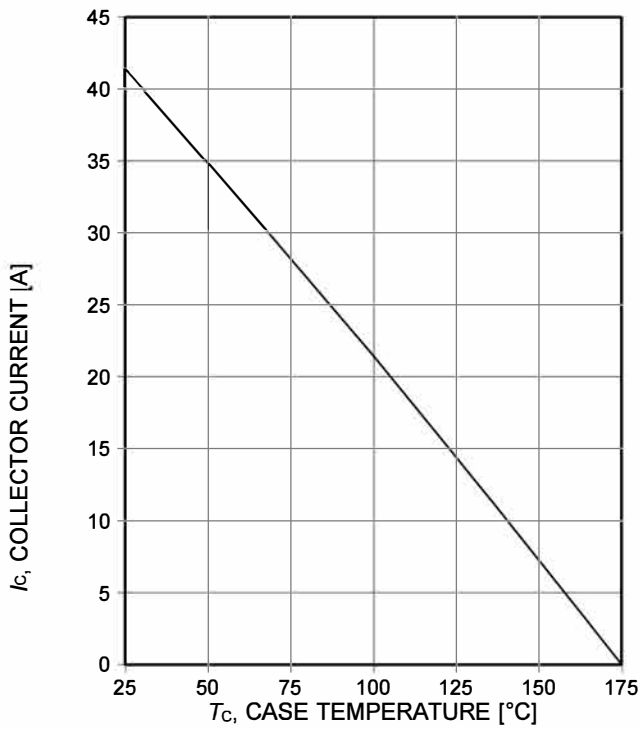


Figure 3. **Collector current as a function of case temperature**

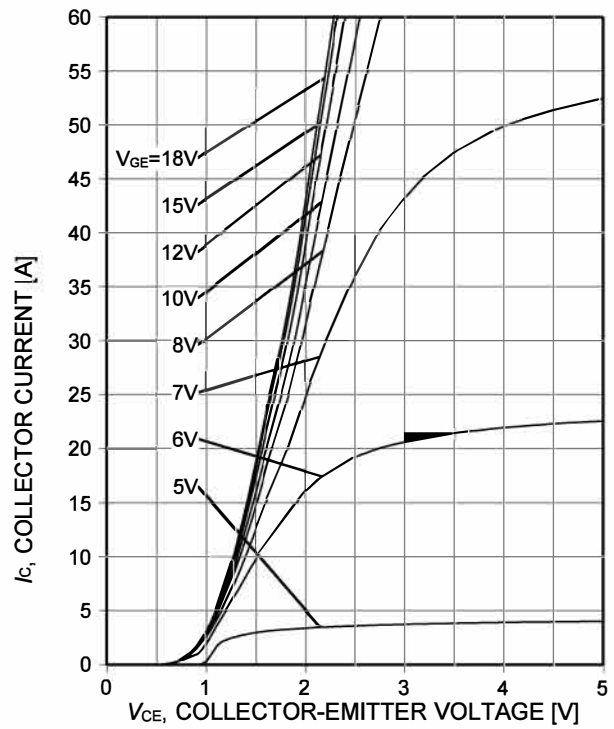


Figure 4. **Typical output characteristic**

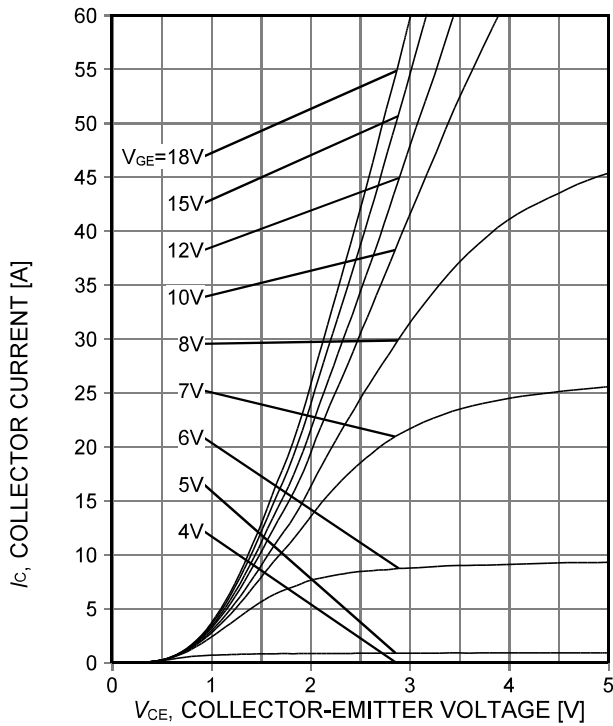


Figure 5. **Typical output characteristic**  
( $T_{vj}=150^{\circ}\text{C}$ )

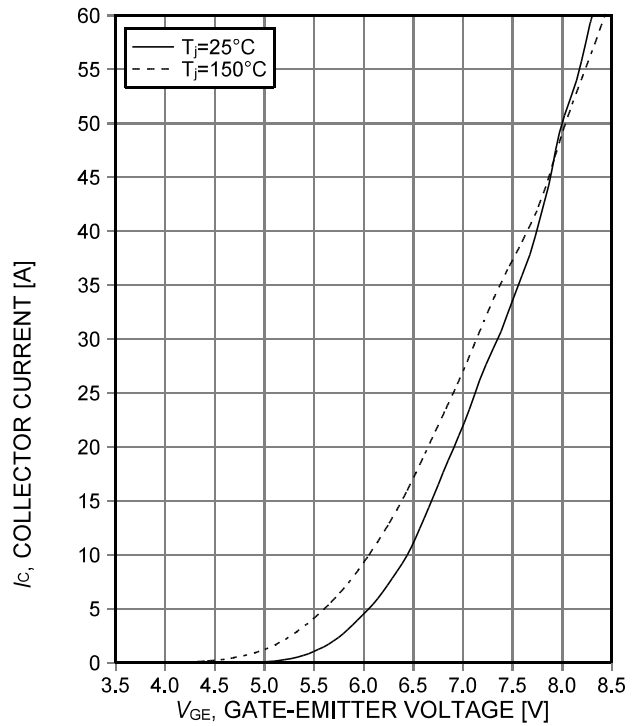


Figure 6. **Typical transfer characteristic**  
( $V_{CE}=20\text{V}$ )

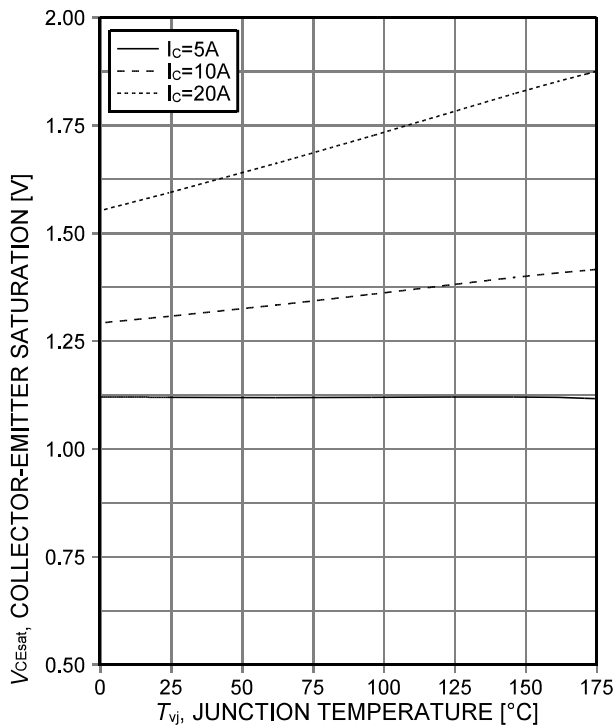


Figure 7. **Typical collector-emitter saturation voltage as a function of junction temperature**

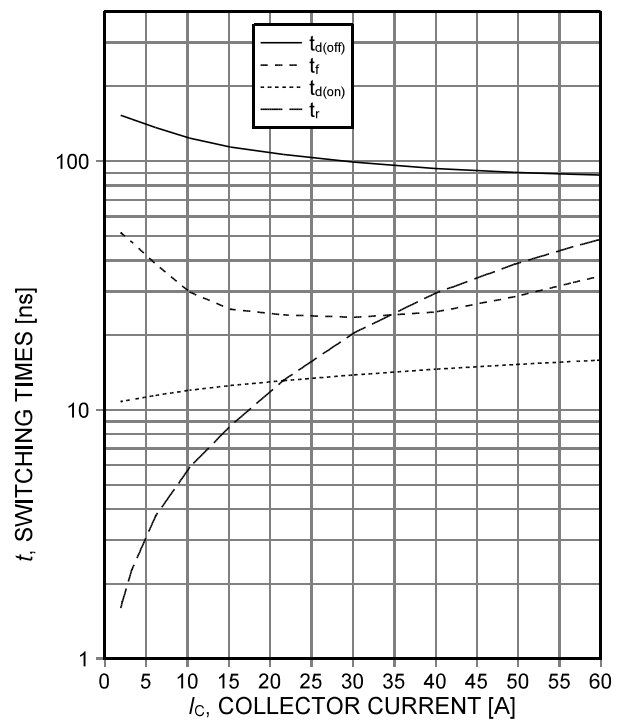


Figure 8. **Typical switching times as a function of collector current**

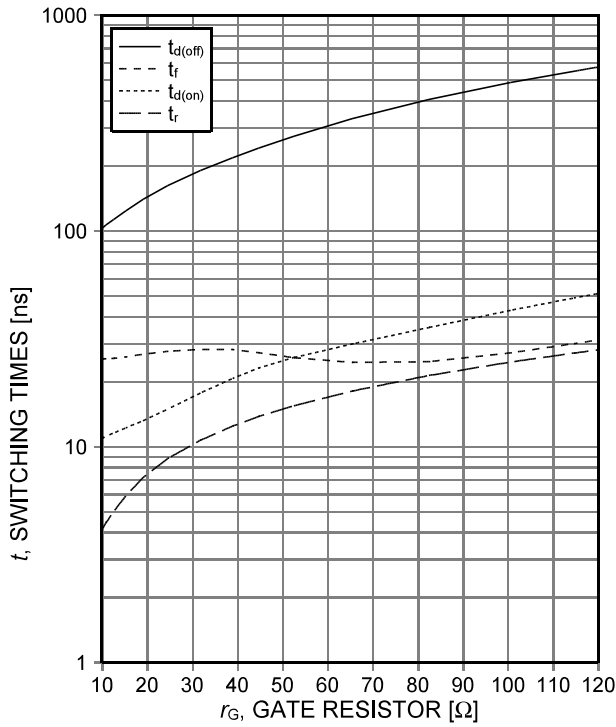


Figure 9. Typical switching times as a function of gate resistor

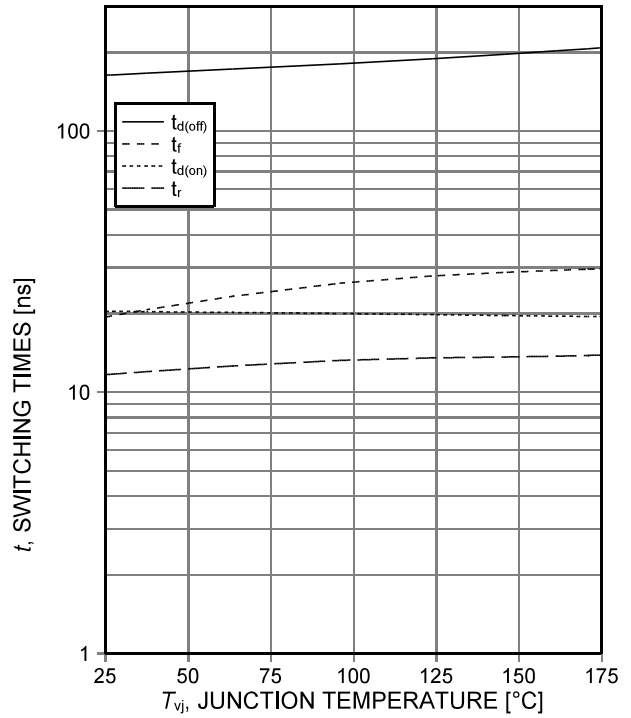


Figure 10. Typical switching times as a function of junction temperature

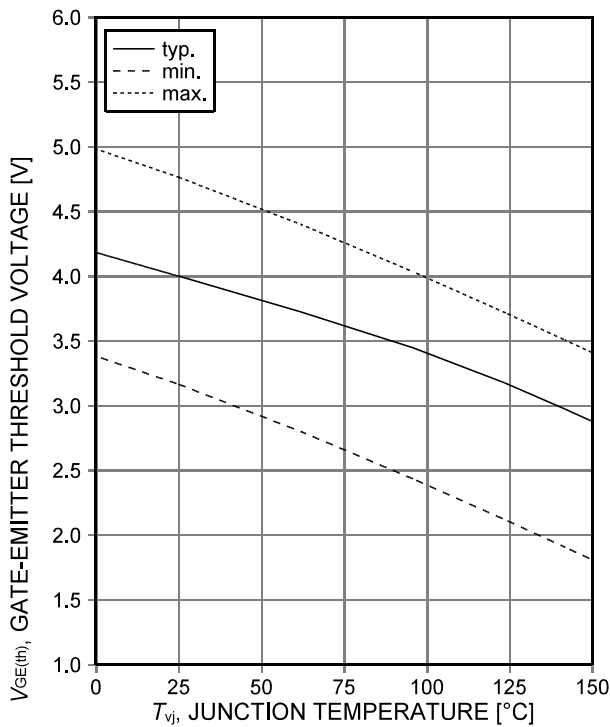


Figure 11. Gate-emitter threshold voltage as a function of junction temperature

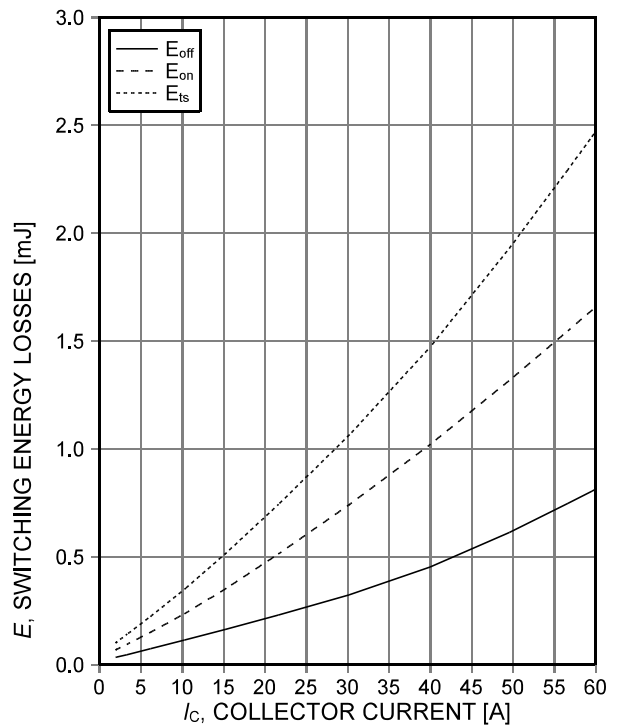


Figure 12. Typical switching energy losses as a function of collector current

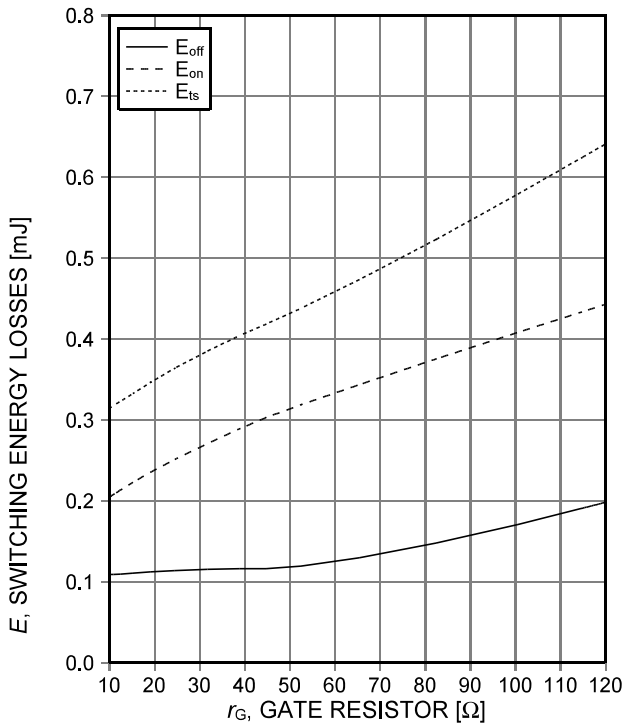


Figure 13. Typical switching energy losses as a function of gate resistor

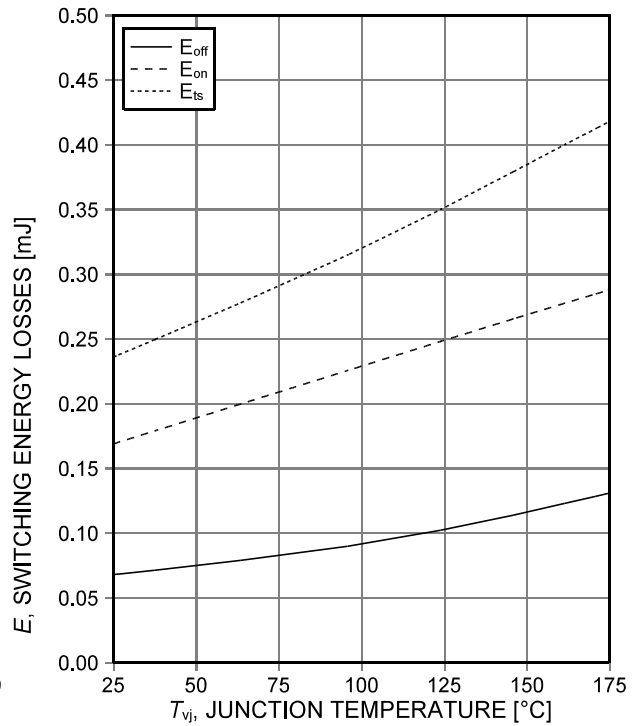


Figure 14. Typical switching energy losses as a function of junction temperature

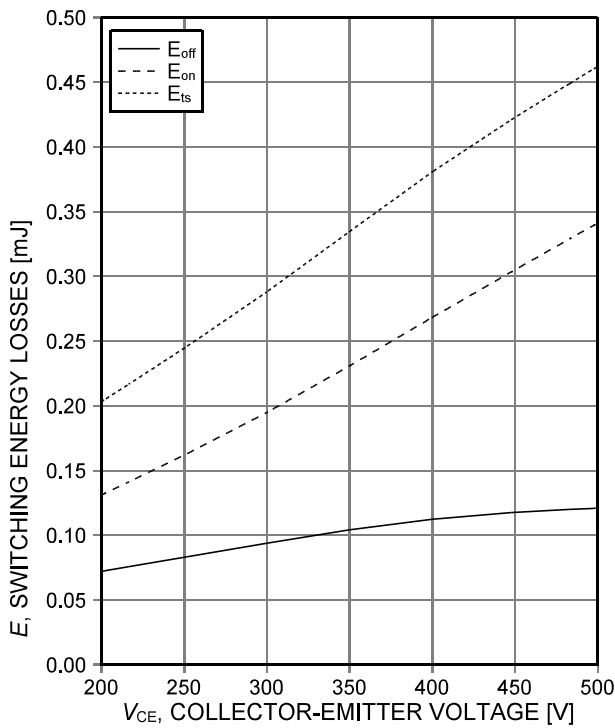


Figure 15. Typical switching energy losses as a function of collector emitter voltage

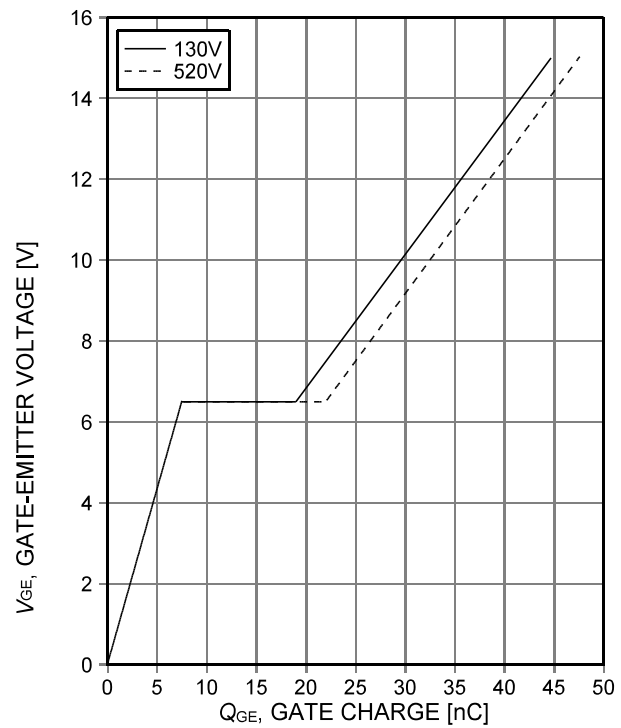


Figure 16. Typical gate charge

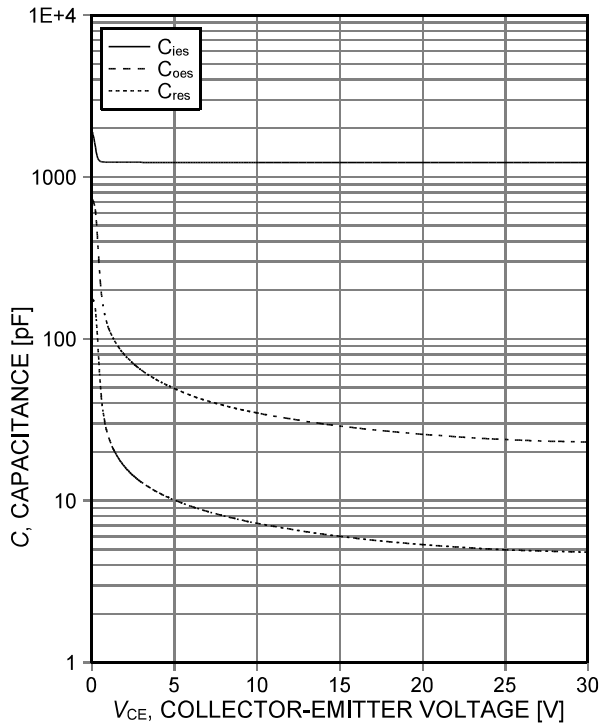


Figure 17. Typical capacitance as a function of collector-emitter voltage

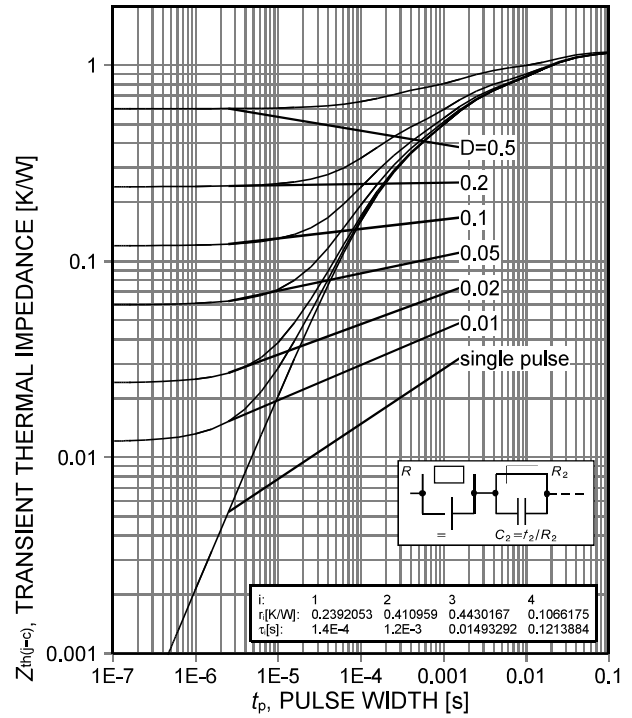


Figure 18. IGBT transient thermal impedance

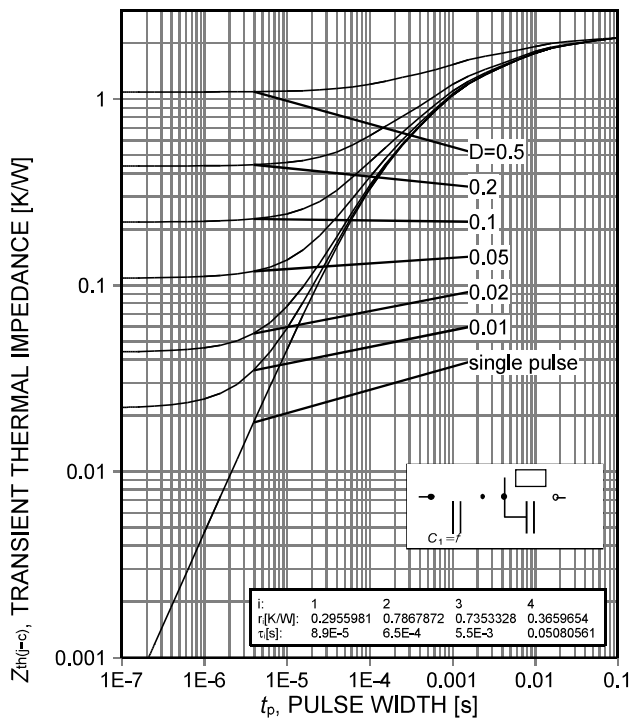


Figure 19. Diode transient thermal impedance as a function of pulse width

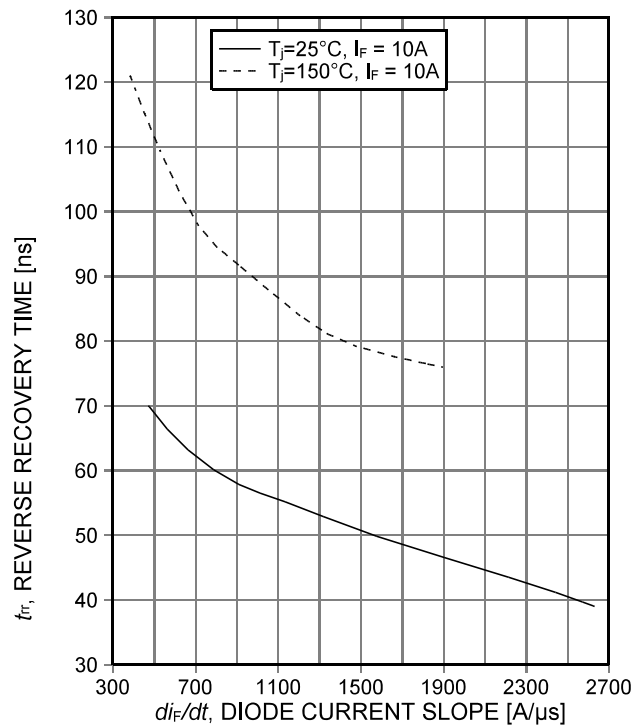
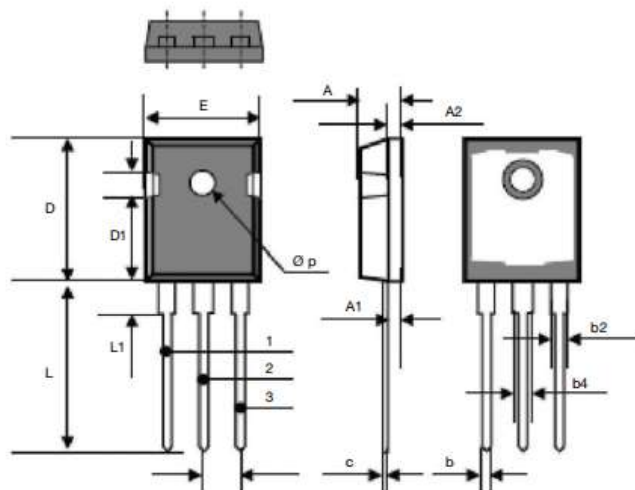


Figure 20. Typical reverse recovery time as a function of diode current slope

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DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.70	5.31	0.185	0.209
A1	2.21	2.59	0.087	0.102
A2	1.50	2.49	0.059	0.098
b	0.99	1.40	0.039	0.055
b2	1.65	2.41	0.065	0.095
b4	2.59	3.43	0.102	0.135
c	0.61 BSC		0.024 BSC	
D	20.80	21.46	0.819	0.845
D1	3.68	5.49	0.145	0.216
(e)	5.46 BSC		0.215 BSC	
E	15.49	16.26	0.610	0.640
L	19.81	20.32	0.780	0.800
L1	4.06	4.50	0.160	0.177
$\text{Ø} p$	3.51	3.66	0.138	0.144